Unit in mm

## TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE

# 2 S K 2 1 6 2

# AUDIO FREQUENCY POWER AMPLIFIER APPLICATION

High Breakdown Voltage :  $V_{DSS} = 180 V$ 

High Forward Transfer Admittance :  $|Y_{fs}| = 0.7 \,\mathrm{S}$  (Typ.)

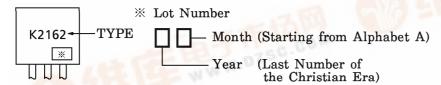
Complementary to 2SJ338

### MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Drain-Source Voltage	V <sub>DSS</sub>	180	V
Gate-Source Voltage	$v_{GSS}$	±20	V
Drain Current	$I_{\mathrm{D}}$	1	A
Power Dissipation (Tc = 25°C)	$P_{\mathbf{D}}$	20	W
Channel Temperature	$\mathrm{T_{ch}}$	150	$^{\circ}\mathrm{C}$
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~150	$^{\circ}\mathrm{C}$

#### **MARKING**

f.dzsc.com



#### ELECTRICAL CHARACTERISTICS (Ta = 25°C)

6.8MAX. 5.2 ± 0.2	2.0MAX.	0.6MAX.
	5.5 ± 0.2	55.014
0.95MAX.	12.0MIN.	0.6MAX.
2.3 2.3		1.1±0.2 2.5MAX.
E ELJ	07	SCICOM
1. GATE 2. DRAIN	(HEA	AT SINK)

INDUSTRIAL APPLICATIONS

3. SOURCE **JEDEC EIAJ** SC-64 **TOSHIBA** 2-7B1B

Weight: 0.36 g

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CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage Current	IGSS	$V_{DS} = 0, V_{GS} = \pm 20 V$	W.A	AFF	±100	nA
Drain-Source Breakdown Voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	180	_	_	V
Gate -Source Cut-off Current	VGS (OFF)	$V_{DS} = 10 \text{ V}, I_{D} = 10 \text{ mA}$	1.4	_	2.8	V
Drain-Source Saturation Voltage	V <sub>DS</sub> (ON)	$I_D = 0.6 A,  V_{GS} = 10 V$	_	1.7	3.0	V
Forward Transfer Admittance	Y <sub>fs</sub>	$V_{DS} = 10 \text{ V}, I_{D} = 0.3 \text{ A}$	_	0.7		S
Input Capacitance	$\mathrm{c}_{\mathrm{iss}}$			170	1	44.0
Output Capacitance	$C_{OSS}$	$V_{DS} = 10 V, V_{GS} = 0,$		45	COC.	$_{ m pF}$
Reverse Transfer Capacitance	$C_{rss}$	$ m f = 1 \ MHz$	701 A	17	_	pr

This transistor is the electrostatic sensitive device. Plese handle with caution.

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